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October 2003

# FDS7779Z

## 30 Volt P-Channel PowerTrench<sup>®</sup> MOSFET

### General Description

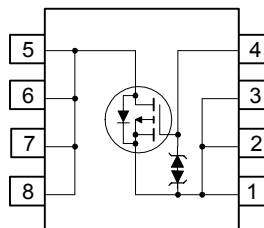
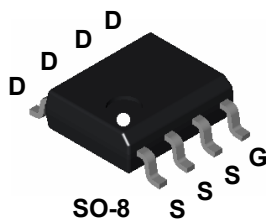
This P-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers, and battery chargers.

These MOSFETs feature faster switching and lower gate charge than other MOSFETs with comparable  $R_{DS(ON)}$  specifications.

The result is a MOSFET that is easy and safer to drive (even at very high frequencies), and DC/DC power supply designs with higher overall efficiency.

### Features

- -16 A, -30 V.  $R_{DS(ON)} = 7.2 \text{ m}\Omega @ V_{GS} = -10 \text{ V}$   
 $R_{DS(ON)} = 11.5 \text{ m}\Omega @ V_{GS} = -4.5 \text{ V}$
- ESD protection diode (note 3)
- High performance trench technology for extremely low  $R_{DS(ON)}$
- High power and current handling capability



### Absolute Maximum Ratings

$T_A = 25^\circ\text{C}$  unless otherwise noted

Symbol	Parameter	Ratings	Units
$V_{DSS}$	Drain-Source Voltage	-30	V
$V_{GSS}$	Gate-Source Voltage	$\pm 25$	V
$I_D$	Drain Current – Continuous (Note 1a)	-16	A
	– Pulsed	-50	
$P_D$	Power Dissipation for Single Operation (Note 1a) (Note 1b) (Note 1c)	2.5	W
		1.2	
		1	
$T_J, T_{STG}$	Operating and Storage Junction Temperature Range	-55 to +150	$^\circ\text{C}$

### Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1a)	50	$^\circ\text{C/W}$
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case (Note 1)	25	

### Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDS7779Z	FDS7779Z	13"	12mm	2500 units

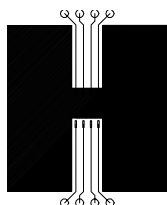
### Electrical Characteristics

T<sub>A</sub> = 25°C unless otherwise noted

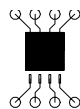
Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
<b>Off Characteristics</b>						
B <sub>V</sub> DSS	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = -250 μA	-30			V
ΔB <sub>V</sub> DSS / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = -250 μA, Referenced to 25°C		-22		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -24 V, V <sub>GS</sub> = 0 V			-1	μA
I <sub>GSS</sub>	Gate-Body Leakage	V <sub>GS</sub> = ±20 V, V <sub>DS</sub> = 0 V			±10	μA
<b>On Characteristics (Note 2)</b>						
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250 μA	-1	-1.5	-3	V
ΔV <sub>GS(th)</sub> / ΔT <sub>J</sub>	Gate Threshold Voltage Temperature Coefficient	I <sub>D</sub> = -250 μA, Referenced to 25°C		5		mV/°C
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = -10 V, I <sub>D</sub> = -16 A V <sub>GS</sub> = -4.5 V, I <sub>D</sub> = -15 A V <sub>GS</sub> = -10 V, I <sub>D</sub> = -16 A, T <sub>J</sub> = 125°C		6 9 8	7.2 11.5 11	mΩ
I <sub>D(on)</sub>	On-State Drain Current	V <sub>GS</sub> = -4.5 V, V <sub>DS</sub> = -5 V	-50			A
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = -5 V, I <sub>D</sub> = -13 A		43		S
<b>Dynamic Characteristics</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = -15 V, V <sub>GS</sub> = 0 V, f = 1.0 MHz		3800		pF
C <sub>oss</sub>	Output Capacitance			980		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			490		pF
R <sub>G</sub>	Gate Resistance	V <sub>GS</sub> = 15 mV, f = 1.0 MHz		3		Ω
<b>Switching Characteristics (Note 2)</b>						
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = -15 V, I <sub>D</sub> = -1 A, V <sub>GS</sub> = -10 V, R <sub>GEN</sub> = 6 Ω		20	36	ns
t <sub>r</sub>	Turn-On Rise Time			9	18	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			100	160	ns
t <sub>f</sub>	Turn-Off Fall Time			55	88	ns
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> = -15 V, I <sub>D</sub> = -16 A, V <sub>GS</sub> = -10 V		70	98	nC
Q <sub>gs</sub>	Gate-Source Charge			10		nC
Q <sub>gd</sub>	Gate-Drain Charge			16		nC
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current				-2.5	A
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = -2.5 A (Note 2)		-0.7	-1.2	V
t <sub>RR</sub>	Reverse Recovery Time	I <sub>F</sub> = -16 A, d <sub>I</sub> /d <sub>t</sub> = 100 A/μs (Note 2)		39		ns
Q <sub>RR</sub>	Reverse Recovery Charge			24		nC

**Notes:**

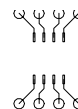
1. R<sub>θJA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>θJC</sub> is guaranteed by design while R<sub>θCA</sub> is determined by the user's board design.



a) 50°C/W (10 sec)  
62.5°C/W steady state  
when mounted on a  
1in<sup>2</sup> pad of 2 oz  
copper



b) 105°C/W when  
mounted on a .04 in<sup>2</sup>  
pad of 2 oz  
copper

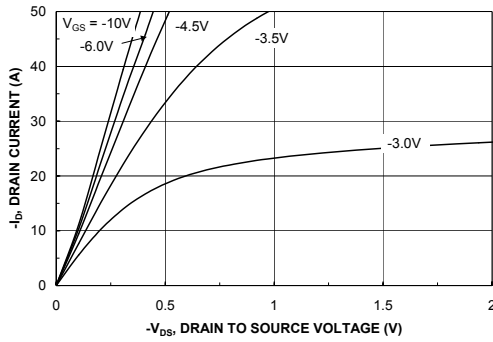


c) 125°C/W when mounted on a  
minimum pad.  
Scale 1 : 1 on letter size paper

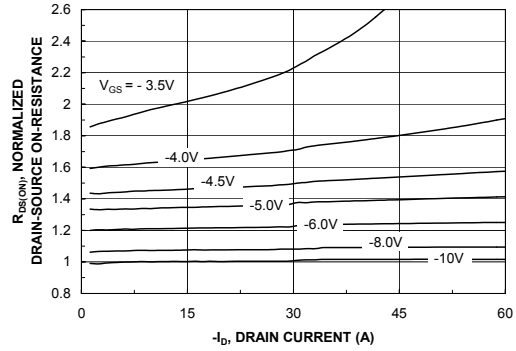
2. Pulse Test: Pulse Width < 300μs, Duty Cycle < 2.0%

3. The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

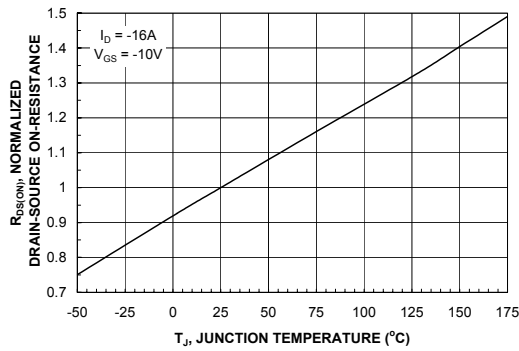
**Typical Characteristics**



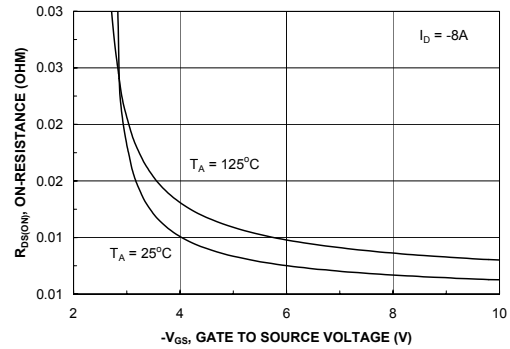
**Figure 1. On-Region Characteristics.**



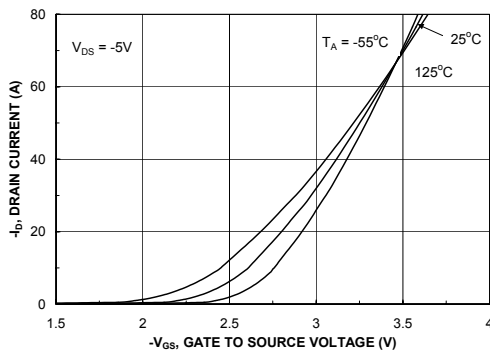
**Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.**



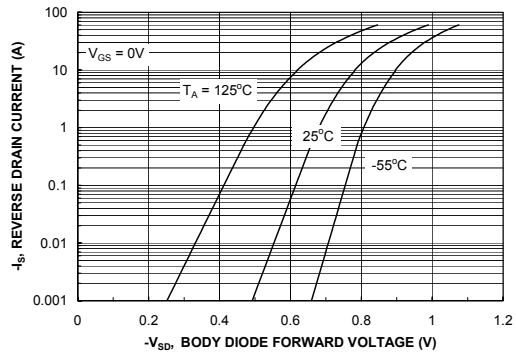
**Figure 3. On-Resistance Variation with Temperature.**



**Figure 4. On-Resistance Variation with Gate-to-Source Voltage.**

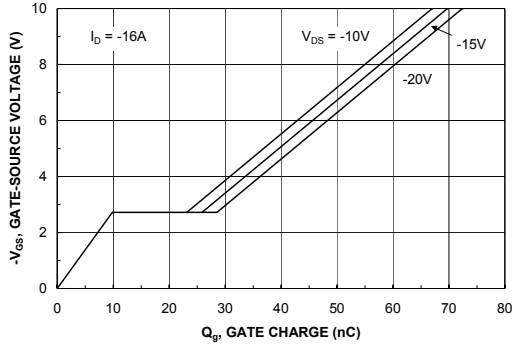


**Figure 5. Transfer Characteristics.**

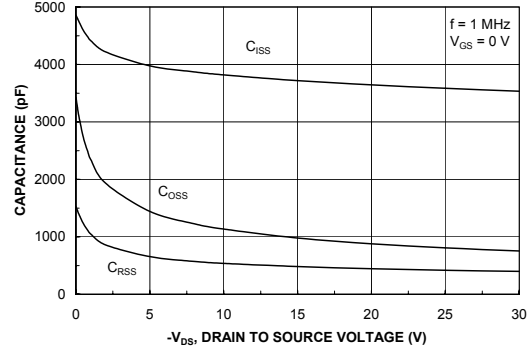


**Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.**

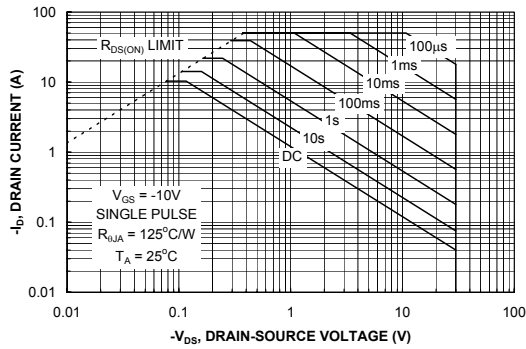
**Typical Characteristics**



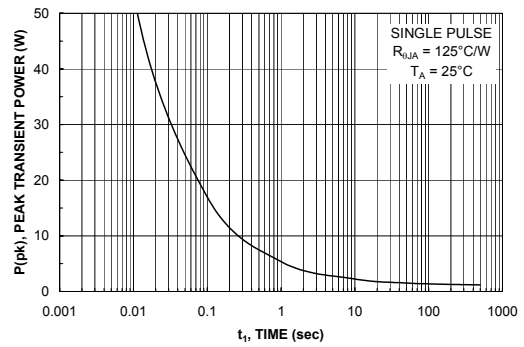
**Figure 7. Gate Charge Characteristics.**



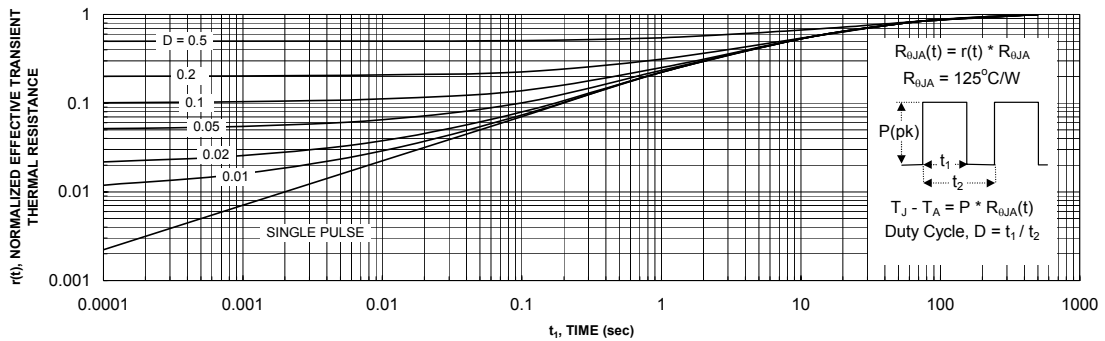
**Figure 8. Capacitance Characteristics.**



**Figure 9. Maximum Safe Operating Area.**



**Figure 10. Single Pulse Maximum Power Dissipation.**



**Figure 11. Transient Thermal Response Curve.**

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

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DOME™	GTO™	MSX™	Quiet Series™	TruTranslation™
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E <sup>2</sup> CMOS™	I <sup>2</sup> C™	OCX™	RapidConnect™	UltraFET®
EnSigna™	ImpliedDisconnect™	OCXPro™	SILENT SWITCHER®	VCX™
FACT™	ISOPLANAR™	OPTOLOGIC®	SMART START™	
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The Power Franchise™	PACMAN™	Stealth™		
Programmable Active Droop™	POP™	SuperSOT™-3		

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